

## *Publications*

### **2016**

208. F. Schäfers, A. Sokolov

[Polarimeter: A Soft X-Ray 8-Axes UHV-Diffractometer](#)

Journal of large-scale research facilities (2016)

207. F. Schäfers

[The crystal monochromator beamline KMC-1](#)

Journal of large-scale research facilities (2016)

206. F. Schäfers, A. Sokolov

[The At-Wavelength Metrology Facility at BESSY-II](#)

Journal of large-scale research facilities (2016)

### **2015**

205. P.C. Pradhan, M. Nayak, G.S. Lodha, A. Sokolov, F. Schäfers

[Erratum: Element-specific structural analysis of Si/B<sub>4</sub>C using resonant x-ray reflectivity](#)

J. Appl. Cryst. (2015) submitted

204. P.C. Pradhan, M. Nayak, G.S. Lodha, A. Sokolov, F. Schäfers

[Determining Chemically and Spatially Resolved Atomic Profile of Low Contrast Interface Structure with High Resolution](#)

Nature Scientific Reports (2015) submitted

203. R. Cimino, V. Baglin, F. Schäfers

[Potential remedies against the high Synchrotron Radiation induced heat load for future highest energy proton circular colliders.](#)

Phys. Rev. Lett. (2015)

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202. Ch. Vogel, M. Radtke, U. Reinholz, F. Schäfers, Ch. Adam

[Chemical State of Chromium, Sulfur and Iron in Sewage Sludge Ash based Phosphorus Fertilizers](#)

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201. F. Senf, F. Bijkerk, F. Eggenstein, A. Erko, G. Gwalt, Q. Huang, R. Kruijs, O. Kutz, S. Lemke, M. Mertin, I. Packe, I. Rudolph, F. Schäfers, F. Siewert, A. Sokolov, Ch. Waberski, Z. Wang, J. Wolf, T. Zeschke

[Highly efficient blazed multilayer grating for energies between 1 keV and 5 keV](#)

Optics Express, to be submitted (2015)

200. S. Hendel, F. Schäfers, M. Hävecker, G. Reichardt, M. Scheer, J. Bahrtdt, K. Lips  
[The EMIL project at BESSY II: beamline design and performance](#)  
AIP Conference Proceedings SRI 2015
199. F. Eggenstein, P. Bischoff, F. Schäfers, T. Schroeter, F. Senf, A. Sokolov, T. Zeschke and A. Erko  
[Survey and adjustment methods applied on an 11-axes high performance reflectometer for synchrotron radiation](#)  
AIP Conference Proceedings SRI 2015
198. P. Baumgärtel, M. Witt, J. Baensch, M. Fabarius, A. Erko, F. Schäfers, H. Schirmacher  
[RAY-UI: A Powerful and Extensible User Interface for RAY](#)  
AIP Conference Proceedings SRI 2015
197. F. Schäfers, P. Bischoff, A. Erko, A. Gaupp, S. Künstner, M. Mast, J.-S. Schmidt, F. Senf, F. Siewert, A. Sokolov, Th. Zeschke  
[The At-Wavelength Metrology Facility for UV- and XUV-Reflection and Diffraction Optics at BESSY-II](#)  
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196. F. Siewert, B. Loechel, J. Buchheim, F. Eggenstein, A. Firsov, G. Gwalt, O. Kutz, St. Lemke, A. Mertsch, B. Nelles, I. Rudolph, F. Schäfers, M. Schmidt, T. Seliger, F. Senf, A. Sokolov, Ch. Waberski, J. Wolf, T. Zeschke, I. Zizak, R. Follath, T. Arnold, F. Pietack, A. Schindler, A. Erko  
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195. K. Lips, T. F. Schulze, D.E. Starr, M. Bär, R.G. Wilks, F. Fenske, F. Ruske, M. Reiche, R. van de Krol, S. Raoux, G. Reichardt, F. Schäfers, S. Hendel, R. Follath, J. Bahrtdt, S. Peredkov, S. DeBeer, M. Hävecker, A. Knop-Gericke, R. Schlögl, B. Rech  
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194. G. F. Dugan, K. G. Sonnad, R. Cimino, T. Ishibashi, F. Schäfers  
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192. F. Eggenstein, P. Bischoff, A. Gaupp, F. Senf, A. Sokolov, T. Zeschke, F. Schäfers  
[\*A reflectometer for at-wavelength characterization of XUV-reflection gratings\*](#)  
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191. A.A. Sokolov, F. Eggenstein, A. Erko, R. Follath, S. Künstner, M. Mast, J.S. Schmidt, F. Senf, F. Siewert, T. Zeschke, F. Schäfers  
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